



Quality and Reliability Report (Quarterly)

July., 2026



Process Related Reliability Test Data

Early Life Failure Rate (ELFR)

1. Test Condition

Performed to accelerate infant mortality failure mechanisms within 1~3 years

Spec: Failure Rate < 300 ppm, Confidence Level: 60%

2. Dynamic RAM Products

Design Rule Technology	Period	Sample Size	No. of Failure/Failure Mode				Failure Rate (ppm)
			Total	Function	DC	Pause	
0.020 μ m CMOS/SPTM	Q3,25	71327	0	0	0	0	15
	Q4,25	21179	0	0	0	0	43
	Q1,26	12010	0	0	0	0	76
	Q2,26	19002	0	0	0	0	48
0.025 μ m CMOS/SPTM	Q3,25	15996	0	0	0	0	82
	Q4,25	10002	0	0	0	0	91
	Q1,26	12685	0	0	0	0	72
	Q2,26	9447	0	0	0	0	97
0.025 μ m CMOS/SPTM	Q3,25	7452	0	0	0	0	119
	Q4,25	7292	0	0	0	0	126
	Q1,26	7700	0	0	0	0	119
	Q2,26	7826	0	0	0	0	117
0.038 μ m CMOS/SPTM	Q3,25	12256	0	0	0	0	74
	Q4,25	12261	0	0	0	0	75
	Q1,26	36815	0	0	0	0	25
	Q2,26	12313	0	0	0	0	74
0.046 μ m CMOS/SPTM	Q3,25	4059	0	0	0	0	137
	Q4,25	3544	0	0	0	0	259
	Q1,26	3366	0	0	0	0	272
	Q2,26	5688	0	0	0	0	161



3. Non-Volatile Memory Products

Design Rule Technology	Period	Sample Size	No. of Failure/Failure Mode				Failure Rate (ppm)
			Total	Function	DC	DR	
0.032 μm CMOS/DPDM 3V/1.8V NAND Flash	Q3,25	3150	0	0	0	0	290
	Q4,25	3150	0	0	0	0	290
	Q1,26	3150	0	0	0	0	290
	Q2,26	3150	0	0	0	0	290
0.046 μm CMOS/DPDM 3V/1.8V NAND Flash	Q3,25	3150	0	0	0	0	290
	Q4,25	3150	0	0	0	0	290
	Q1,26	3150	0	0	0	0	290
	Q2,26	-	-	-	-	-	-
0.045 μm CMOS/DPTM 3V/1.8V Serial Flash	Q3,25	3150	0	0	0	0	290
	Q4,25	3150	0	0	0	0	290
	Q1,26	3150	0	0	0	0	290
	Q2,26	3150	0	0	0	0	290
0.058 μm CMOS/DPTM 3V/1.8V Serial Flash	Q3,25	3150	0	0	0	0	290
	Q4,25	3150	0	0	0	0	290
	Q1,26	3150	0	0	0	0	290
	Q2,26	3150	0	0	0	0	290
0.09 μm CMOS/DPTM 3V/1.8V serial Flash	Q3,25	3150	0	0	0	0	290
	Q4,25	3150	0	0	0	0	290
	Q1,26	-	-	-	-	-	-
	Q2,26	-	-	-	-	-	-



High-Temperature Operating Life Test (HTOL)

1. Test Condition

Condition: Dynamic operating condition with $V_{cc} = 3.6V/2.7V/1.9V/1.575V$ for $3.3V/2.5V/1.8V/1.5V$ products, $T=125^{\circ}C$, $f=1.0MHz/1.25MHz/1.25MHz/1.25MHz$ for synchronous SDRAMs/DDR/DDRII/DDRIII

Dynamic operating read condition with $V_{cc} = 3.6V/1.95V$ for $3.3V/1.8V$ products, $T = 125^{\circ}C$, $f = 1\text{ MHz}$ for Non-Volatile Memory

Duration: Test time points at 500 hrs, and 1000 hrs.

2. Dynamic RAM Products

2.1 By Device Type

Product Type	Part No.	Design Rule	Period	No. of Samples	No. of Fails	Reject Information
256M × 16 1.575V	W634GU6RB	0.020 μm	Q3,25	231	0	
			Q4,25	231	0	
			Q1,26	231	0	
			Q2,26	231	0	
256M × 16 1.575V	W634GU6QB	0.025s μm	Q3,25	231	0	
			Q4,25	231	0	
			Q1,26	231	0	
			Q2,26	231	0	
128M × 16 1.575V	W632GU6NB	0.025 μm	Q3,25	231	0	
			Q4,25	231	0	
			Q1,26	231	0	
			Q2,26	231	0	
64M × 16 1.575V	W631GG6MB	0.038 μm	Q3,25	231	0	
			Q4,25	231	0	
			Q1,26	231	0	
			Q2,26	231	0	
128M × 16 1.9V	W9751G6KB	0.046 μm	Q3,25	231	0	
			Q4,25	231	0	
			Q1,26	231	0	
			Q2,26	231	0	



2.2 By Process

Design Rule Technology	Period	No. of Samples	No. of Fails	Reject Information
0.020 μm CMOS/SPTM	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	231
0.025s μm CMOS/SPTM	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.025 μm CMOS/SPTM	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.038 μm CMOS/SPTM	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.046 μm CMOS/SPTM	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	



3. Non-Volatile Memory Products

3.1 By Device Type

Product Type	Part No.	Design Rule	Period	No. of Samples	No. of Fails	Reject Information
2G, 3V NAND FLASH	W25N02KV	0.032 μm	Q3,25	231	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	
2G, 1.8V NAND FLASH	W25N02KW	0.032 μm	Q3,25	-	-	
			Q4,25	231	0	
			Q1,26	-	-	
			Q2,26	-	-	
2G, 3V NAND FLASH	W29N02KV	0.032 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	231	0	
1G, 3V SPI NAND FLASH	W25N01KV	0.032 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	231	0	
			Q2,26	-	-	
4G, 3V NAND FLASH	W29N04GV	0.046 μm	Q3,25	231	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	
2G, 3V NAND FLASH	W29N01HZ	0.046 μm	Q3,25	-	-	
			Q4,25	231	0	
			Q1,26	-	-	
			Q2,26	-	-	
1G, 3V SPI NAND FLASH	W25N01GV	0.046 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	231	0	
			Q2,26	-	-	



128M,1.8V SERIAL FLASH	W25Q12PW	0.045 μm	Q3,25	231	0	
			Q4,25	231	0	
			Q1,26	231	0	
			Q2,26	231	0	
512M,1.8V SERIAL FLASH	W25Q512NW	0.058 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	231	0	
256M,1.8V SERIAL FLASH	W25Q256JW	0.058 μm	Q3,25	231	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	
128M, 3V SPI NAND FLASH	W25Q128JV	0.058 μm	Q3,25	-	-	
			Q4,25	231	0	
			Q1,26	231	0	
			Q2,26	-	-	
2M,3V SERIAL FLASH	W25X20CL	0.09 μm	Q3,25	231	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	

3.2 By Process

Design Rule Technology	Period	No. of Samples	No. of Fails	Reject Information
0.032 μm CMOS/DPDM 3V/1.8V NAND	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.046 μm CMOS/DPDM 3V/1.8V NAND Flash	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	-	-	



0.045 μm CMOS/DPTM 3V/1.8V Serial Flash	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.058 μm CMOS/DPTM 3V/1.8V Serial Flash	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.09 μm CMOS/DPTM 3V Serial Flash	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	-	-	
	Q2,26	-	-	

High-Temperature Storage Life Test (HTSL)

1. Test Condition

Condition: T = 150°C

Duration: Test time points at 500 hrs, and 1000 hrs. (Need to do precondition)

2. Dynamic RAM Products

2.1 By Device Type

Product Type	Part No.	Design Rule	Period	No. of Samples	No. of Fails	Reject Information
256M $\times$ 16 1.575V	W634GU6RB	0.020 μm	Q3,25	231	0	
			Q4,25	231	0	
			Q1,26	231	0	
			Q2,26	231	0	
256M $\times$ 16 1.575V	W634GU6QB	0.025s μm	Q3,25	231	0	
			Q4,25	231	0	
			Q1,26	231	0	
			Q2,26	231	0	
128M $\times$ 16 1.575V	W632GG6NB	0.025 μm	Q3,25	231	0	
			Q4,25	231	0	
			Q1,26	231	0	
			Q2,26	231	0	



64M × 16 1.575V	W631GG6MB	0.038 μm	Q3,25	231	0	
			Q4,25	231	0	
			Q1,26	231	0	
			Q2,26	231	0	
128M × 16 1.8V	W9751G6KB	0.046 μm	Q3,25	231	0	
			Q4,25	231	0	
			Q1,26	231	0	
			Q2,26	231	0	

2.2 By Process

Design Rule Technology	Period	No. of Samples	No. of Fails	Reject Information
0.020 μm CMOS/SPTM	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.025s μm CMOS/SPTM	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.025 μm CMOS/SPTM	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.038 μm CMOS/SPTM	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.046 μm CMOS/SPTM	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	



3. Non-Volatile Memory Products

3.1 By Device Type

Product Type	Part No.	Design Rule	Period	No. of Samples	No. of Fails	Reject Information
2G, 3V NAND FLASH	W25N02KV	0.032 μm	Q3,25	231	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	
2G, 1.8V NAND FLASH	W25N02KW	0.032 μm	Q3,25	-	-	
			Q4,25	231	0	
			Q1,26	-	-	
			Q2,26	-	-	
2G, 3V NAND FLASH	W29N02KV	0.032 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	231	0	
1G, 3V SPI NAND FLASH	W25N01KV	0.032 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	231	0	
			Q2,26	-	-	
4G, 3V NAND FLASH	W29N04GV	0.046 μm	Q3,25	231	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	
1G, 1.8V NAND FLASH	W29N01HZ	0.046 μm	Q3,25	-	-	
			Q4,25	231	0	
			Q1,26	-	-	
			Q2,26	-	-	
1G, 3V SPI NAND FLASH	W25N01GV	0.046 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	231	0	
			Q2,26	-	-	



128M,1.8V SERIAL FLASH	W25Q12PW	0.045 μm	Q3,25	231	0	
			Q4,25	231	0	
			Q1,26	231	0	
			Q2,26	231	0	
512M,1.8V SERIAL FLASH	W25Q512NW	0.058 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	231	0	
512M, 3V SPI NAND FLASH	W25Q128JV	0.058 μm	Q3,25	-	-	
			Q4,25	231	0	
			Q1,26	231	0	
			Q2,26	-	-	
256M,1.8V SERIAL FLASH	W25Q256JW	0.058 μm	Q3,25	231	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	
2M,3V SERIAL FLASH	W25X20CL	0.09 μm	Q3,25	231	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	



3.2 By Process

Design Rule Technology	Period	No. of Samples	No. of Fails	Reject Information
0.032 μm CMOS/DPDM 3V/1.8V NAND	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.046 μm CMOS/DPDM 3V/1.8V NAND Flash	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	-	-	
0.045 μm CMOS/DPTM 3V/1.8V Serial Flash	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.058 μm CMOS/DPTM 3V/1.8V Serial Flash	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.09 μm CMOS/DPTM 3V Serial Flash	Q3,25	231	0	
	Q4,25	-	-	
	Q1,26	-	-	
	Q2,26	-	-	



Data Retention Test (DR)

1. Test Condition

Condition: T = 150°C

Duration: Test time points at 500 hrs, and 1000 hrs.

2. Non-Volatile Memory Products

2.1 By Device Type

Product Type	Part No.	Design Rule	Period	No. of Samples	No. of Fails	Reject Information
2G, 3V NAND FLASH	W25N02KV	0.032 μm	Q3,25	231	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	
2G, 1.8V NAND FLASH	W25N02KW	0.032 μm	Q3,25	-	-	
			Q4,25	231	0	
			Q1,26	-	-	
			Q2,26	-	-	
2G, 3V NAND FLASH	W29N02KV	0.032 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	231	0	
1G, 3V SPI NAND FLASH 1G, 3V	W25N01KV	0.032 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	231	0	
			Q2,26	-	-	
4G, 3V NAND FLASH	W29N04GV	0.046 μm	Q3,25	231	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	
1G, 1.8V NAND FLASH	W29N01HZ	0.046 μm	Q3,25	-	-	
			Q4,25	231	0	
			Q1,26	-	-	
			Q2,26	-	-	



1G, 3V NAND FLASH	W25N01GV	0.046 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	231	0	
			Q2,26	-	-	
128M, 1.8V SERIAL FLASH	W25Q12PW	0.045 μm	Q3,25	231	0	
			Q4,25	231	0	
			Q1,26	231	0	
			Q2,26	231	0	
512M, 1.8V SERIAL FLASH	W25Q512NW	0.058 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	231	0	
128M, 3V SPI NAND FLASH	W25Q128JV	0.058 μm	Q3,25	-	-	
			Q4,25	231	0	
			Q1,26	-	-	
			Q2,26	-	-	
256M, 1.8V SERIAL FLASH	W25Q256JW	0.058 μm	Q3,25	231	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	
2M, 3V SERIAL FLASH	W25X20CL	0.09 um	Q3,25	231	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	



3.2 By Process

Design Rule Technology	Period	No. of Samples	No. of Fails	Reject Information
0.032 μm CMOS/DPDM 3V/1.8V NAND	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.046 μm CMOS/DPDM 3V/1.8V NAND Flash	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	-	-	
0.045 μm CMOS/DPTM 3V/1.8V Serial Flash	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.058 μm CMOS/DPTM 3V/1.8V Serial Flash	Q3,25	231	0	
	Q4,25	231	0	
	Q1,26	231	0	
	Q2,26	231	0	
0.09 μm CMOS/DPTM 3V Serial Flash	Q3,25	231	0	
	Q4,25	-	-	
	Q1,26	-	-	
	Q2,26	-	-	



Endurance Cycling With Data Retention Test

Room Temperature cycling with DR

1. Test Condition

Condition: T = Room temperature, Vcc = 3.6V/1.95V for Endurance Cycling test, and

T = Room temperature, Vcc = 3.6V/1.95V, f = 10 MHz for room temperature operation life test

Duration: 1K, 10K, 100K cycles for Endurance Cycling test and 500 hrs for room temperature operation life test

2. Non-Volatile Memory Products

2.1 By Device Type

Product Type	Part No.	Design Rule	Period	No. of Samples	No. of Fails	Reject Information
2G, 3V NAND FLASH	W25N02KV	0.032 μm	Q3,25	114	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	
2G, 1.8V NAND FLASH	W25N02KW	0.032 μm	Q3,25	-	-	
			Q4,25	114	0	
			Q1,26	-	-	
			Q2,26	-	-	
2G, 3V NAND FLASH	W29N02KV	0.032 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	114	0	
1G, 3V SPI NAND FLASH 1G, 3V	W25N01KV	0.032 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	114	0	
			Q2,26	-	-	
4G, 3V NAND FLASH	W29N04GV	0.046 μm	Q3,25	114	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	
1G, 1.8V NAND FLASH	W29N01HZ	0.046 μm	Q3,25	-	-	
			Q4,25	114	0	
			Q1,26	-	-	
			Q2,26	-	-	



1G, 3V SPI NAND FLASH	W25N01GV	0.046 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	114	0	
			Q2,26	-	-	
128M, 1.8V SERIAL FLASH	W25Q12PW	0.045 μm	Q3,25	114	0	
			Q4,25	114	0	
			Q1,26	114	0	
			Q2,26	114	0	
512M, 1.8V SERIAL FLASH	W25Q512NW	0.058 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	114	0	
			Q2,26	114	0	
512M, 3V SPI NAND FLASH	W25Q128JV	0.058 μm	Q3,25	-	-	
			Q4,25	114	0	
			Q1,26	114	0	
			Q2,26	-	-	
256M, 1.8V SERIAL FLASH	W25Q256JW	0.058 μm	Q3,25	114	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	
2M, 3V SERIAL FLASH	W25X20CL	0.09 μm	Q3,25	114	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	



2.2 By Process

Design Rule Technology	Period	No. of Samples	No. of Fails	Reject Information
0.032 μm CMOS/DPDM 3V/1.8V NAND	Q3,25	114	0	
	Q4,25	114	0	
	Q1,26	114	0	
	Q2,26	114	0	
0.046 μm CMOS/DPDM 3V/1.8V NAND Flash	Q3,25	114	0	
	Q4,25	114	0	
	Q1,26	114	0	
	Q2,26	-	-	
0.045 μm CMOS/DPTM 3V/1.8V Serial Flash	Q3,25	114	0	
	Q4,25	114	0	
	Q1,26	114	0	
	Q2,26	114	0	
0.058 μm CMOS/DPTM 3V/1.8V Serial Flash	Q3,25	114	0	
	Q4,25	114	0	
	Q1,26	114	0	
	Q2,26	114	0	
0.09 μm CMOS/DPTM 3V Serial Flash	Q3,25	114	0	
	Q4,25	114	0	
	Q1,26	-	-	
	Q2,26	-	-	



High Temperature cycling with DR

1. Test Condition

Condition: T = 85°C, Vcc = 3.6V/1.95V for Endurance Cycling test, and T = 125°C for High Temperature Data Retention test

Duration:

NOR flash:

1K, 10K, 100K cycles for Endurance Cycling test and 100 hrs of High Temperature Data Retention test for 1K, 10K, 100K cycling region

NAND flash:

1K, 10K, 100K cycles for Endurance Cycling test and 100 hrs of High Temperature Data Retention test for 1K,10K cycling region

2. Non-Volatile Memory Products

2.1 By Device Type

Product Type	Part No.	Design Rule	Period	No. of Samples	No. of Fails	Reject Information
2G, 3V NAND FLASH	W25N02KV	0.032 μm	Q3,25	117	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	
2G, 3V NAND FLASH	W25N02KW	0.032 μm	Q3,25	-	-	
			Q4,25	117	0	
			Q1,26	-	-	
			Q2,26	-	-	
2G, 3V NAND FLASH	W29N02KV	0.032 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	117	0	
1G, 3V SPI NAND FLASH 1G, 3V	W25N01KV	0.032 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	117	0	
			Q2,26	-	-	
4G, 3V NAND FLASH	W29N04GV	0.046 μm	Q3,25	117	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	



2G, 3V NAND FLASH	W25N01HZ	0.046 μm	Q3,25	-	-	
			Q4,25	117	0	
			Q1,26	-	-	
			Q2,26	-	-	
1G, 3V SPI NAND FLASH	W25N01GV	0.046 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	117	0	
			Q2,26	-	-	
128M, 1.8V SERIAL FLASH	W25Q12PW	0.045 μm	Q3,25	117	0	
			Q4,25	117	0	
			Q1,26	117	0	
			Q2,26	117	0	
512M, 1.8V SERIAL FLASH	W25Q512NW	0.058 μm	Q3,25	-	-	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	117	0	
512M, 3V SPI NAND FLASH	W25Q128JV	0.058 μm	Q3,25	-	-	
			Q4,25	117	0	
			Q1,26	117	0	
			Q2,26	-	-	
256M, 1.8V SERIAL FLASH	W25Q256JW	0.058 μm	Q3,25	117	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	
2M, 3V SERIAL FLASH	W25X20CL	0.09 μm	Q3,25	117	0	
			Q4,25	-	-	
			Q1,26	-	-	
			Q2,26	-	-	



2.2 By Process

Design Rule Technology	Period	No. of Samples	No. of Fails	Reject Information
0.032 μm CMOS/DPDM 3V/1.8V NAND	Q3,25	117	0	
	Q4,25	117	0	
	Q1,26	117	0	
	Q2,26	117	0	
0.046 μm CMOS/DPDM 3V/1.8V NAND Flash	Q3,25	117	0	
	Q4,25	117	0	
	Q1,26	117	0	
	Q2,26	-	-	
0.045 μm CMOS/DPDM 3V/1.8V NAND Flash	Q3,25	117	0	
	Q4,25	117	0	
	Q1,26	117	0	
	Q2,26	117	0	
0.058 μm CMOS/DPTM 3V/1.8V Serial Flash	Q3,25	117	0	
	Q4,25	117	0	
	Q1,26	117	0	
	Q2,26	117	0	
0.09 μm CMOS/DPTM 3V Serial Flash	Q3,25	117	0	
	Q4,25	117	0	
	Q1,26	-	-	
	Q2,26	-	-	



Electrostatic Discharge (ESD) Test

1.1 Test Condition

Human Body Mode.

According to JS-001

1.2 Dynamic RAM Products

Product Type	Design Rule (μm)	No. of DUT	Pass Voltage (HBM)
128M x 16 (1.9 V)	0.046	24	> 2 kV
64M x 16 (1.575 V)	0.038	24	> 2 kV
128M x 16 (1.575 V)	0.025	24	> 2 kV
256M x 16 (1.575 V)	0.025	24	> 2 kV
256M x 16 (1.575 V)	0.020	24	> 2 kV

1.3 Non-Volatile Memory Products

Product Type	Design Rule (μm)	No. of DUT	Pass Voltage (HBM)
2G NAND FLASH(3V)	0.032	12	> 2 kV
128M SERIAL FLASH (1.8V)	0.045	12	> 2 kV
512M SERIAL FLASH (1.8V)	0.058	12	> 2 kV



2.1 Test Condition

Charged Device Mode.

According to JS-002

2.2 Dynamic RAM Products

Product Type	Design Rule (μm)	No. of DUT	Pass Voltage (CDM)
128M x 16 (1.9 V)	0.046	3	> 750V
64M x 16 (1.575 V)	0.038	3	> 750V
128M x 16 (1.575 V)	0.025	3	> 750V
256M x 16 (1.575 V)	0.025	3	> 750V
256M x 16 (1.575 V)	0.020	3	> 750V

2.3 Non-Volatile Memory Products

Product Type	Design Rule (μm)	No. of DUT	Pass Voltage (CDM)
2G NAND FLASH(3V)	0.032	3	> 750V
128M SERIAL FLASH (1.8V)	0.045	3	> 750V
512M SERIAL FLASH (1.8V)	0.058	3	> 750V



Latch-Up Test

1. Test Condition

According to JEDEC -78.

2. Dynamic RAM Products

Product Type	Design Rule (μm)	No. of DUT	Pass Current
128M x 16 (1.9 V)	0.046	6	>100 mA
64M x 16 (1.575 V)	0.038	6	>100 mA
128M x 16 (1.575 V)	0.025	6	>100 mA
256M x 16 (1.575 V)	0.025	6	>100 mA
256M x 16 (1.575 V)	0.020	6	>100 mA

3. Non-Volatile Memory Products

Product Type	Design Rule	No. of DUT	Pass Voltage
2G NAND FLASH(3V)	0.032	6	>100 mA
128M SERIAL FLASH (1.8V)	0.045	6	>100 mA
512M SERIAL FLASH (1.8V)	0.058	6	>100 mA